

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office


» Se

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **2** of **1064971** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set
Results Key:**JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 CMOS dynamic comparators for pipeline A/D converters***Sumanen, L.; Waltari, M.; Hakkarainen, V.; Halonen, K.;*

Circuits and Systems, 2002. ISCAS 2002. IEEE International Symposium on, Volume: 5, 26-29 May 2002

Pages:V-157 - V-160 vol.5

[\[Abstract\]](#)
[\[PDF Full-Text \(423 KB\)\]](#)

IEEE CNF

2 AC-DC transfer control loop of the PTB highly accurate AC power so*Stojanovic, B.; Zirpel, R.;*

Precision Electromagnetic Measurements, 1990. CPEM '90 Digest., Conference on, 11-14 June 1990

Pages:138 - 139

[\[Abstract\]](#)
[\[PDF Full-Text \(124 KB\)\]](#)

IEEE CNF

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved